TOSHIBA Field Effect Transistor Silicon N Channel MOS Type(-MOSV)

TPCA8009-H

TENTATIVE

High Speed and High Efficiency DC-DC Converters

Unit: mm

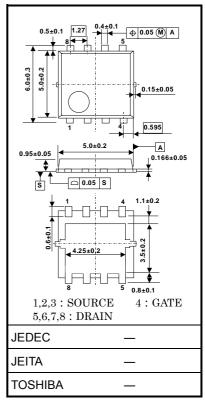
- Small footprint due to small and thin package
- High speed switching
- Small gate charge: $Q_g = 10nC$ (typ.)
- Low drain-source ON resistance: $RDS(ON) = 240m\Omega$ (typ.)
- High forward transfer admittance: $|Y_{fs}| = S \text{ (typ.)}$
- Low leakage current: $I_{DSS} = 100 \mu A (max) (V_{DS} = 100 V)$
- Enhancement mode: $V_{th} = 2 \text{ to } 4V \text{ (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA)}$

Maximum Ratings (Ta = 25°C)

Characte	ristics	Symbol	Rating	Unit
Drain-source voltage		V_{DSS}	150	V
Drain-gate voltage (R	$R_{GS} = 20 \text{ k}\Omega$)	V_{DGR}	150	V
Gate-source voltage		V _{GSS}	±20	V
Drain current	DC (Note 1)	I _D	7	Α
Diain cuitent	Pulsed (Note 1)	I _{DP}	14	^
Drain power dissipati	on (Tc=25)	P_{D}	45	W
Drain power dissipati	on $(t = 10 s)$ (Note 2a)	P_{D}	2.8	W
Drain power dissipati	on $(t = 10 s)$ (Note 2b)	P _D	1.6	W
Single pulse avalanch	ne energy (Note 3)	E _{AS}	34	mJ
Avalanche current		I _{AR}	7	Α
Repetitive avalanche	energy c=25) (Note 4)	E _{AR}	1.5	mJ
Channel temperature		T _{ch}	150	°C
Storage temperature	range	T _{stg}	-55~150	°C

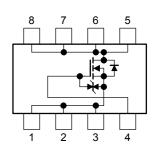
Note: For (Note 1), (Note 2), (Note 3), (Note 4), please refer to the next page.

This transistor is an electrostatic sensitive device. Please handle with caution.



Weight: 0.08 g (typ.)

Circuit Configuration

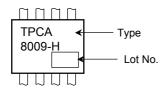


Thermal Characteristics

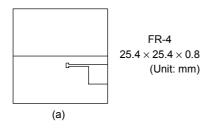
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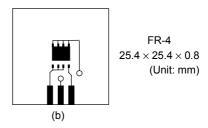
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case (Tc=25)	R _{th (ch-c)}	2.78	°C/W
Thermal resistance, channel to ambient (t = 10 s) (Note 2a)	R _{th (ch-a)}	44.6	°C/W
Thermal resistance, channel to ambient (t = 10 s) (Note 2b)	R _{th (ch-a)}	78.1	°C/W

Marking (Note 5)

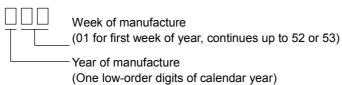


- Note 1: Please use devices on condition that the channel temperature is below 150°C.
- Note 2: (a) Device mounted on a glass-epoxy board (a)
- (b) Device mounted on a glass-epoxy board (b)





- Note 3: $V_{DD} = 50~V$, $T_{ch} = 25^{\circ}C$ (initial) , L = 1~mH , $R_G = 25~\Omega$, $I_{AR} = 7~A$
- Note 4: Repetitive rating: pulse width limited by max channel temperature
- Note 5: * Weekly code: (Three digits)



Electrical Characteristics (Ta = 25°C)

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Cha	Characteristics		Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I _{GSS}	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	± 10	μΑ
Drain cut-OFF cu	ırrent	I _{DSS}	V _{DS} = 150 V, V _{GS} = 0 V	_	_	100	μΑ
Drain-source breakdown voltage		V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	150	_	_	V
		V _{(BR) DSX}	$I_D = 10 \text{ mA}, V_{GS} = -5 \text{ V}$ 150		_	_	v
		V _{(BR) DSX}	$I_D = 10 \text{ mA}, V_{GS} = -20 \text{ V}$	100	_	_	
Gate threshold voltage		V _{th}	V _{DS} = 10 V, I _D = 1mA	2.0	_	4.0	V
Drain-source ON resistance		R _{DS} (ON)	V _{GS} = 10 V, I _D = 3.5A	_	0.23	(0.35)	Ω
Forward transfer admittance		Y _{fs}	V _{DS} = 10 V, I _D = 3.5A	TBD	TBD	_	S
Input capacitance	9	C _{iss}		_	600	_	
Reverse transfer capacitance		C _{rss}	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	20	_	pF
Output capacitance		Coss		_	220	_	
Switching time	Rise time	t _r	ACS 10 A 10 = 3.2 V COLL	_	(7)	_	- ns
	Turn-ON time	t _{on}		_	(17)	_	
	Fall time	t _f		_	(13)	_	
	Turn-OFF time	t _{off}	$V_{DD} \simeq 75V$ Duty $\leq 1\%$, $t_W = 10 \ \mu s$	_	(70)	_	
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \simeq 120 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 7\text{A}$	_	(10)		nC
Gate-source charge 1		Q _{gs1}			(7.6)		
Gate-drain ("miller") charge		Q _{gd}]	_	(2.4)	_	
Gate switch charge		Q _{SW}		_	(3.7)	_	

Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit	
Drain reverse current	Pulse	(Note 1)	I _{DRP}	_	_	_	14	Α
Forward voltage (diode)			V_{DSF}	$I_{DR} = 7A$, $V_{GS} = 0$ V	_	_	-2.0	V

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